Search Notes

Application/Control No.	F	
10/665,316	A	
Examiner	1	

Jason M. Han

Applicant(s)/Patent under Reexamination
ALBOU ET AL.
Art Unit

SEARCHED				
Class	Subclass	Dațe	Examiner	
362	296-297	4/21/2006	ЈМН	
362	299-300	4/21/2006	JMH	
362	302	4/21/2006	JMH	
362	307-309	4/21/2006	ЈМН	
362	311	4/21/2006	JMH	
362	326-328	4/21/2006	JMH	
362	335-338	4/21/2006	ЈМН	
362	339-341	4/21/2006	JMH	
362	346	4/21/2006	JMH	
362	507	4/21/2006	JMH	
362	516-518	4/21/2006	JMH	
362	520-522	4/21/2006	JMH	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	-PGPUB) - rintout	4/21/2006	JMH	

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
Search Update - EAST (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT) - See Printout	4/21/2006	JMH
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